

<b>Notice of References Cited</b>	Application/Control No. 09/850,975	Applicant(s)/Patent Under Reexamination TOYAMA ET AL.	
	Examiner BRIAN P. YENKE	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,778,698	08-2004	Prakash et al.	382/164
X	B	US-6,778,697	08-2004	Shin et al.	382/164
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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